
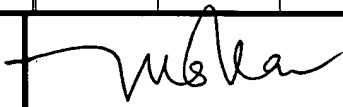
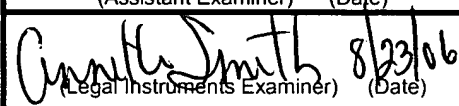


Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/813,011	NOGUCHI, HIDEKAZU	
	Examiner	Art Unit	
	Hiep Nguyen	2816	

ISSUE CLASSIFICATION									
ORIGINAL					CROSS REFERENCE(S)				
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
327		333		327	306	315			
INTERNATIONAL CLASSIFICATION				326	60	62	80		
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Hiep Nguyen (Assistant Examiner) (Date)		 TUAN T. LAM PRIMARY EXAMINER (Primary Examiner)	Total Claims Allowed: 18	
 (Legal Instruments Examiner) (Date)			O.G. Print Claim(s) 1	O.G. Print Fig. 1

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original
1	①						
2	2						
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20	20						